



Alpide DTU



Sezione di Torino

A 1.2 Gb/s Data Transmission Unit in
CMOS 0.18 μm for the ALICE Inner
Tracking System front-end ASIC

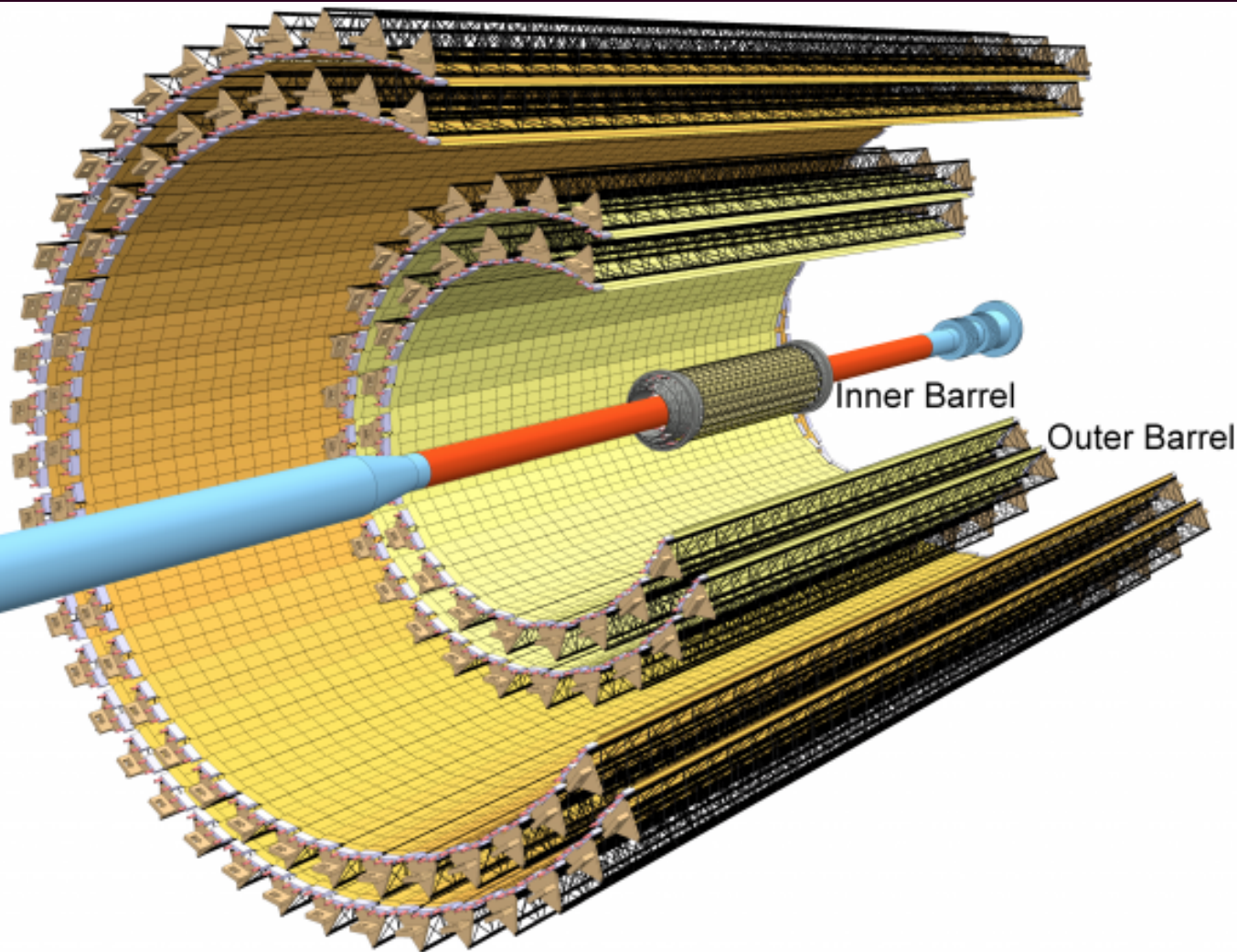
G. Mazza for the ALICE collaboration



ALICE ITS Upgrade



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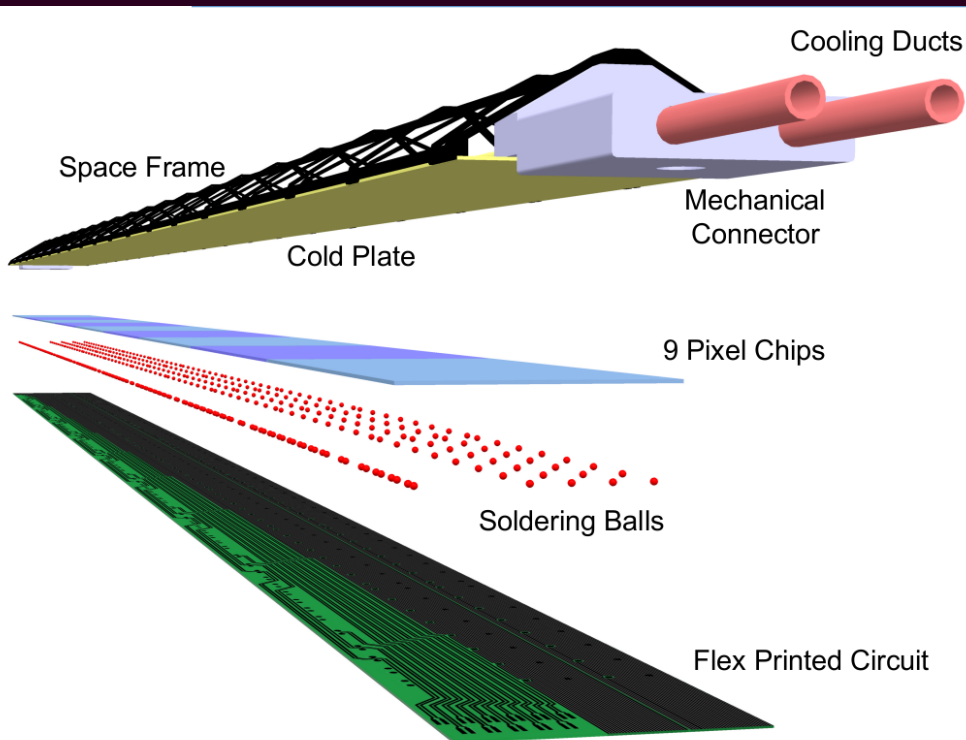
- 7 layers based on CMOS sensors
- 48 inner barrel staves (290 mm) on 3 layers
- 54 middle barrel staves (900 mm) on 2 layers
- 90 outer barrel staves (1500 mm) on 2 layers
- Total active area $\sim 10\text{m}^2$
- Pixel size $28 \times 28 \mu\text{m}^2$
- ~ 24000 pixel chips (12.5×10^9 pixels)



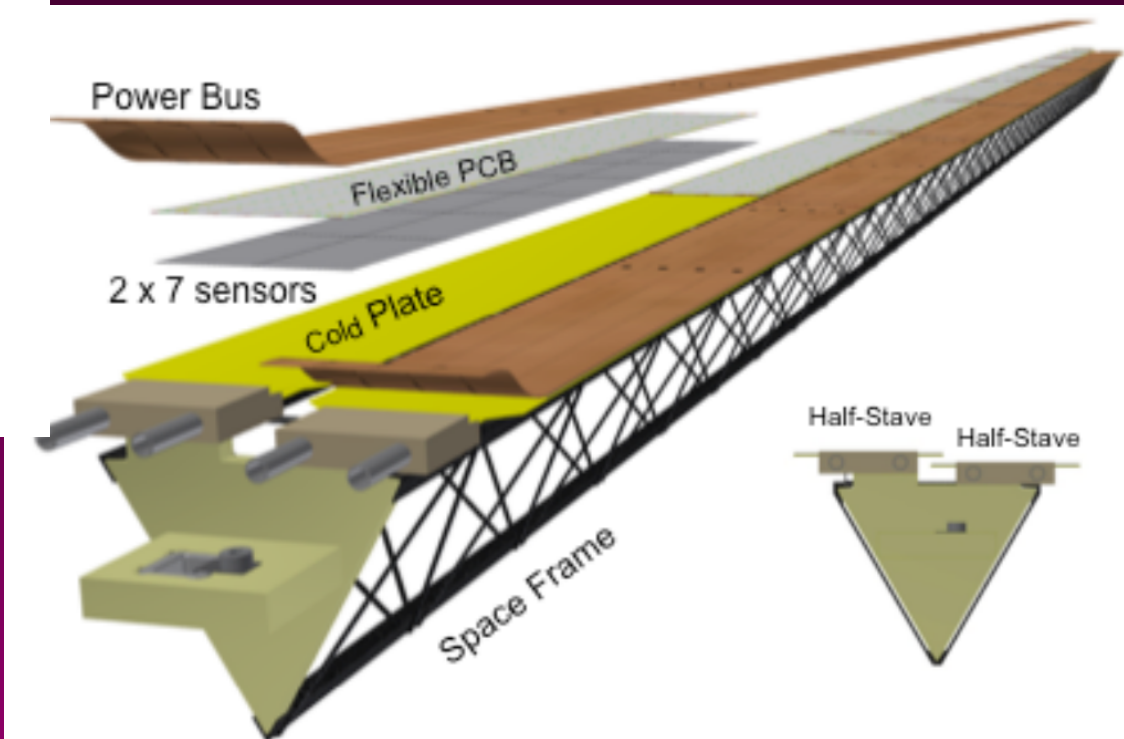
Staves



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module : 2×7 chips
MB Layers : 2×4 modules/stave
OB Layers : 2×7 modules/stave



IB Layers : 9 chips/stave



DTU specs



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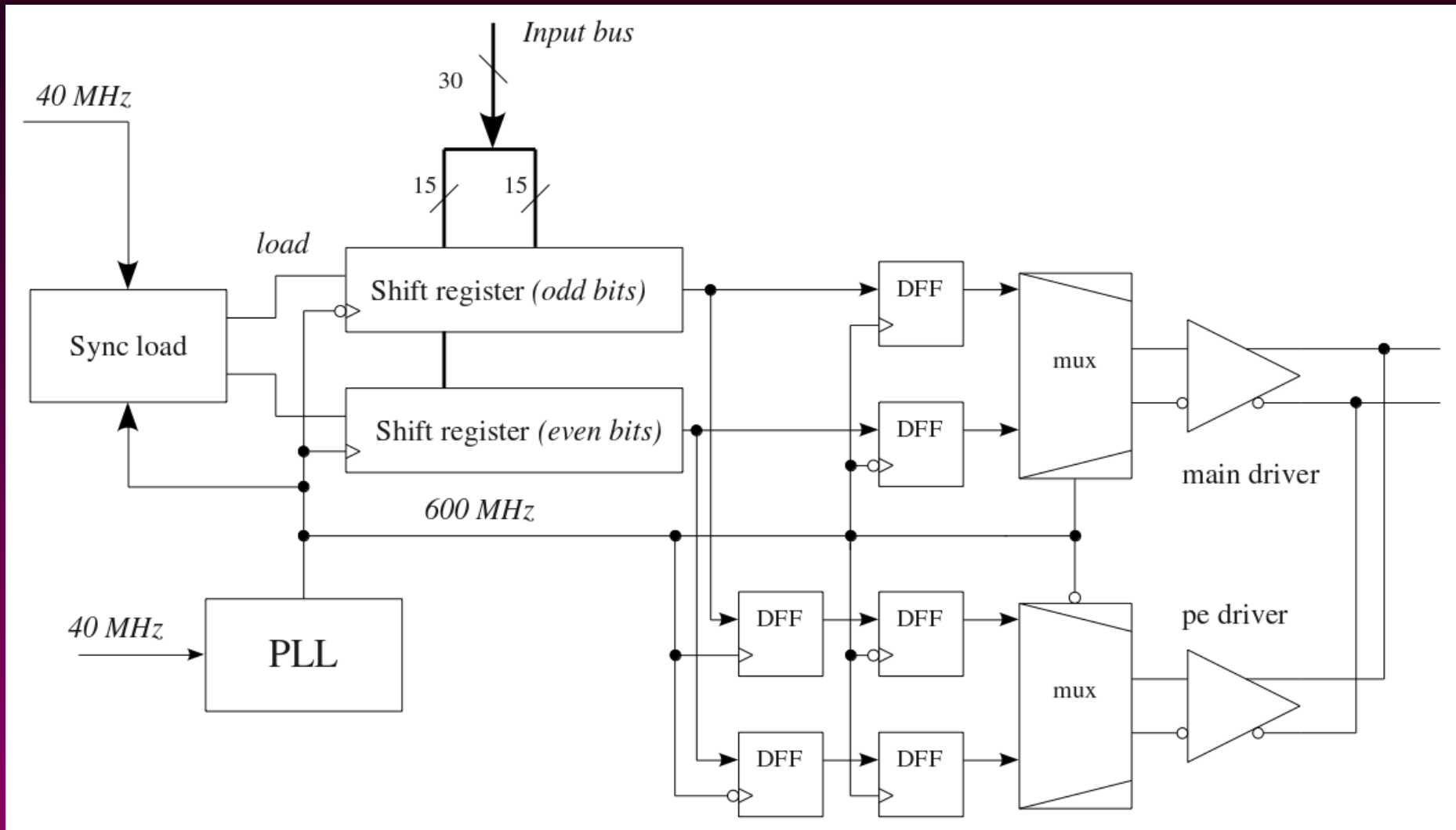
<i>Input clock</i>	<i>40 MHz</i>
<i>Transmission clock</i>	<i>600 MHz</i>
<i>Transmission type</i>	<i>Double Data Rate (DDR)</i>
<i>Line/Data rate (inner layers)</i>	<i>1.2/0.96 Gb/s (IB)</i>
<i>Line/Data rate (outer layers)</i>	<i>400/320 Mb/s (MB-OB)</i>
<i>Data encoding</i>	<i>8b10b</i>
<i>Electrical protocol</i>	<i>(pseudo)LVDS</i>
<i>Technology</i>	<i>CIS 0.18 μm</i>



DTU scheme



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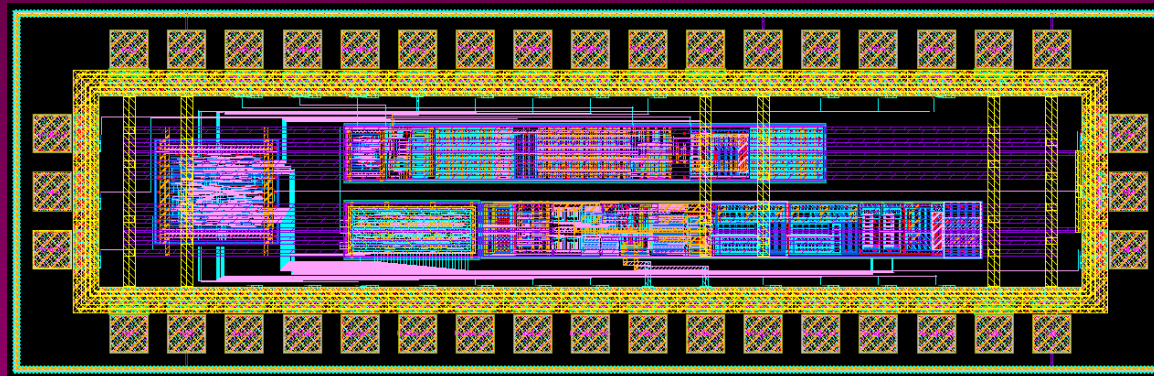
DTU implementations



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DTU has been implemented in two ASICs :

- * Alpide v3 (and v4)
- * DTU test chip
 - Layout size : 2.4 mm × 0.72 mm
 - 40 pads
 - includes PLL, serializer and driver + test features

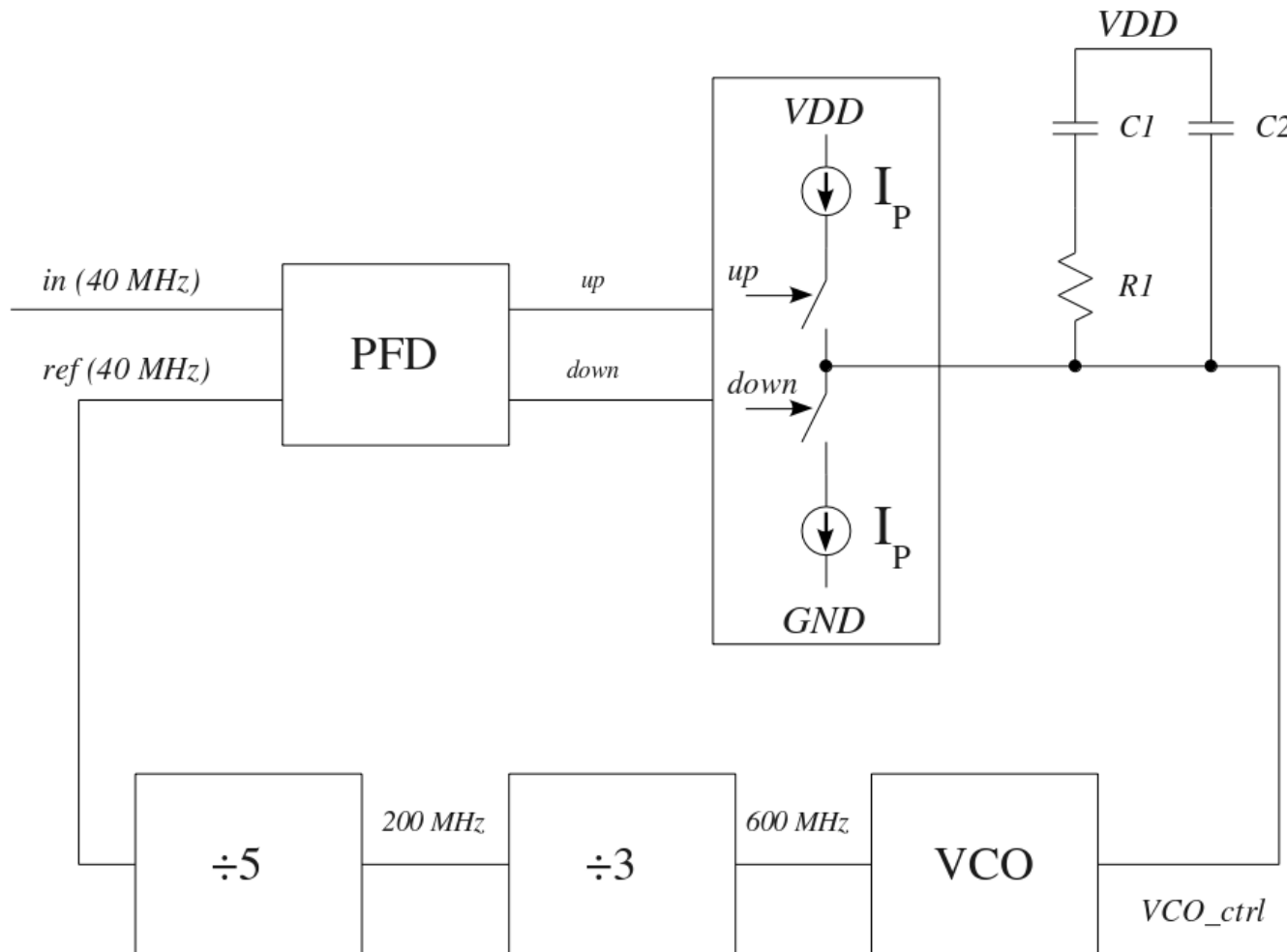




PLL scheme



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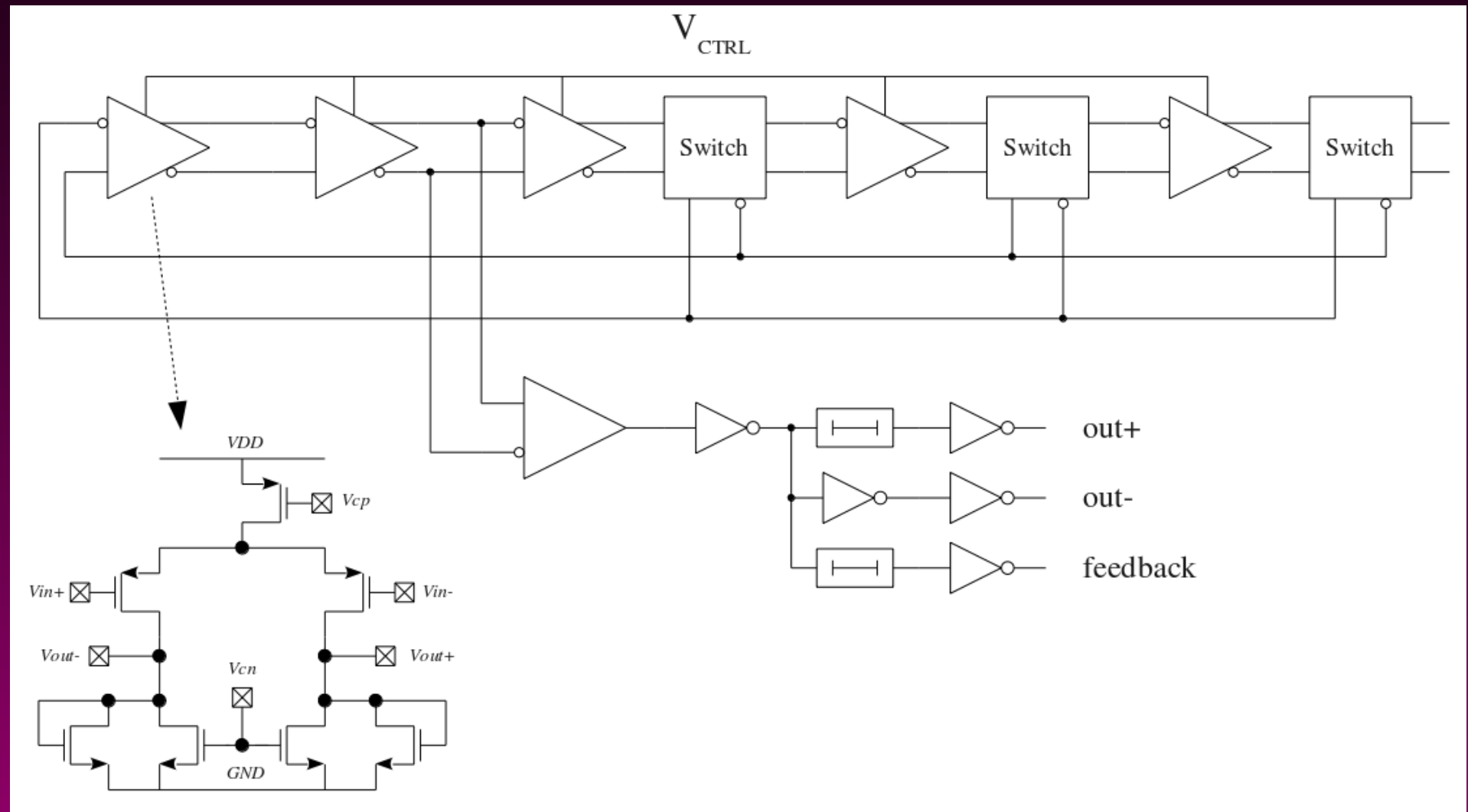
- * Input frequency 40 MHz
- * Area : $1059 \times 120 \mu\text{m}^2$ (form factor set by Alpide floorplan requirements)
- * Differential ring oscillator VCO (range 500-700 MHz)
- * SEU tolerant frequency divider
- * Lock time $\sim 10 \mu\text{s}$
- * Power : 15.4 mW @ 1.2V



VCO scheme



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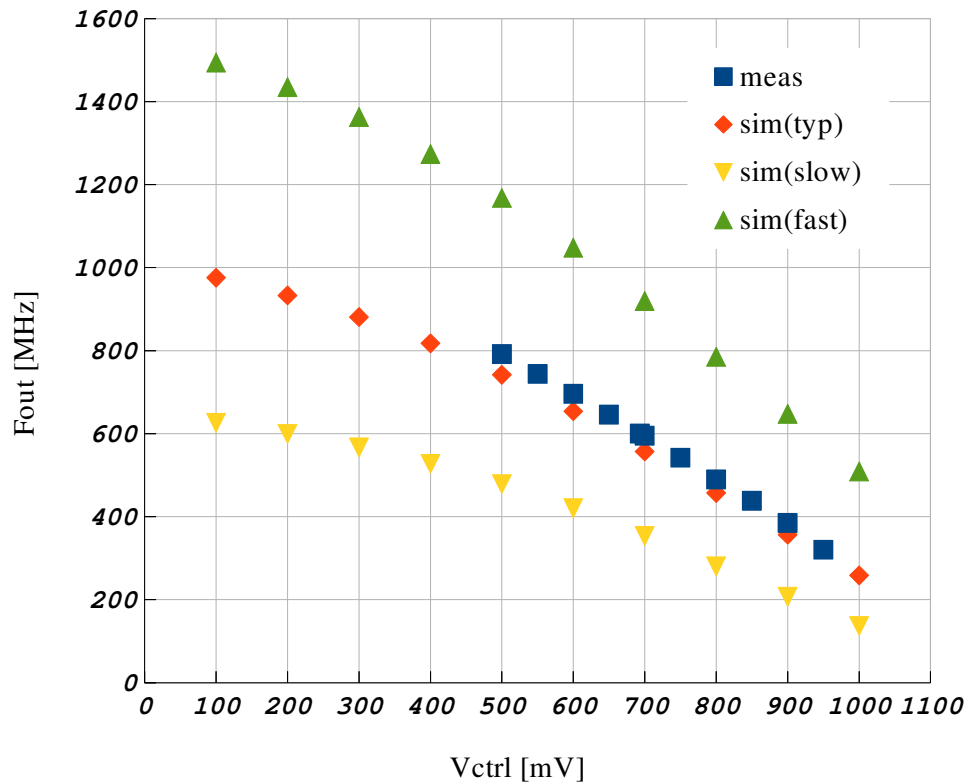


VCO frequency spread

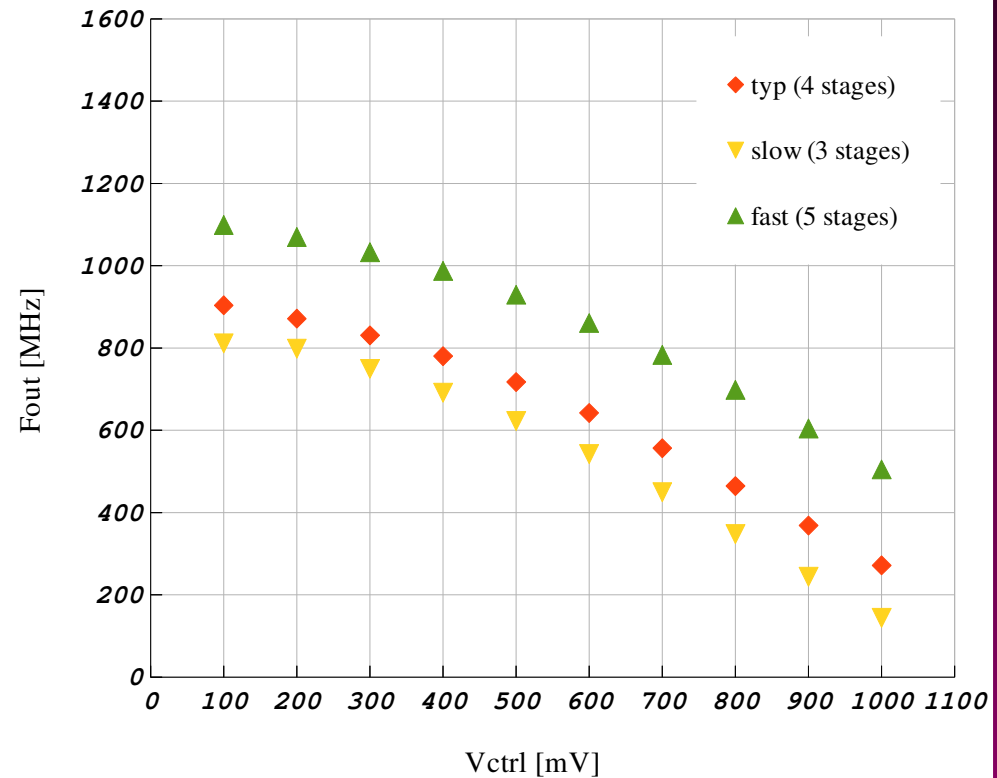


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VCO with 4 stages (sim & measurements)



VCO with 3-4-5 stages (sim only)

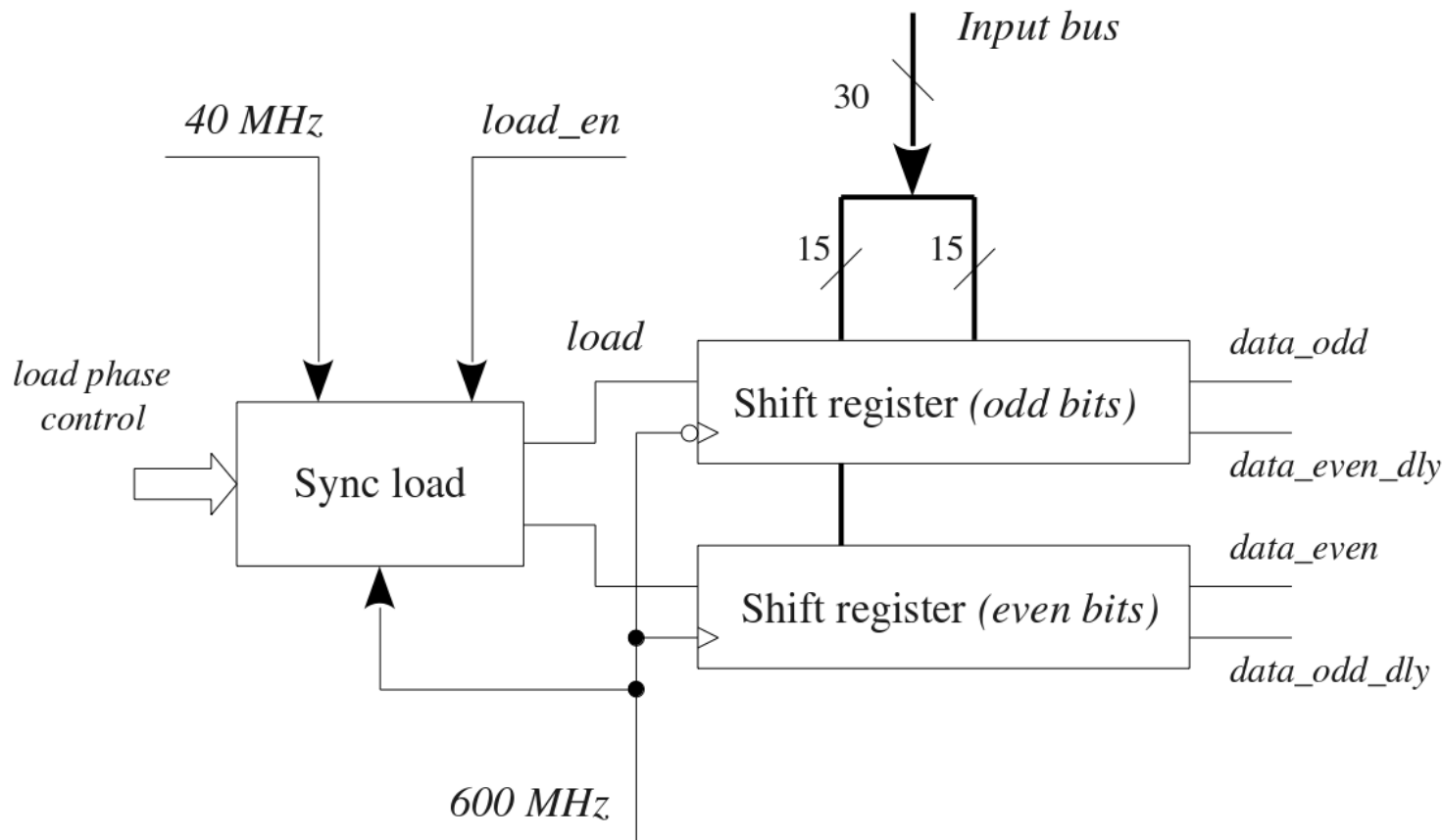




Serializer scheme



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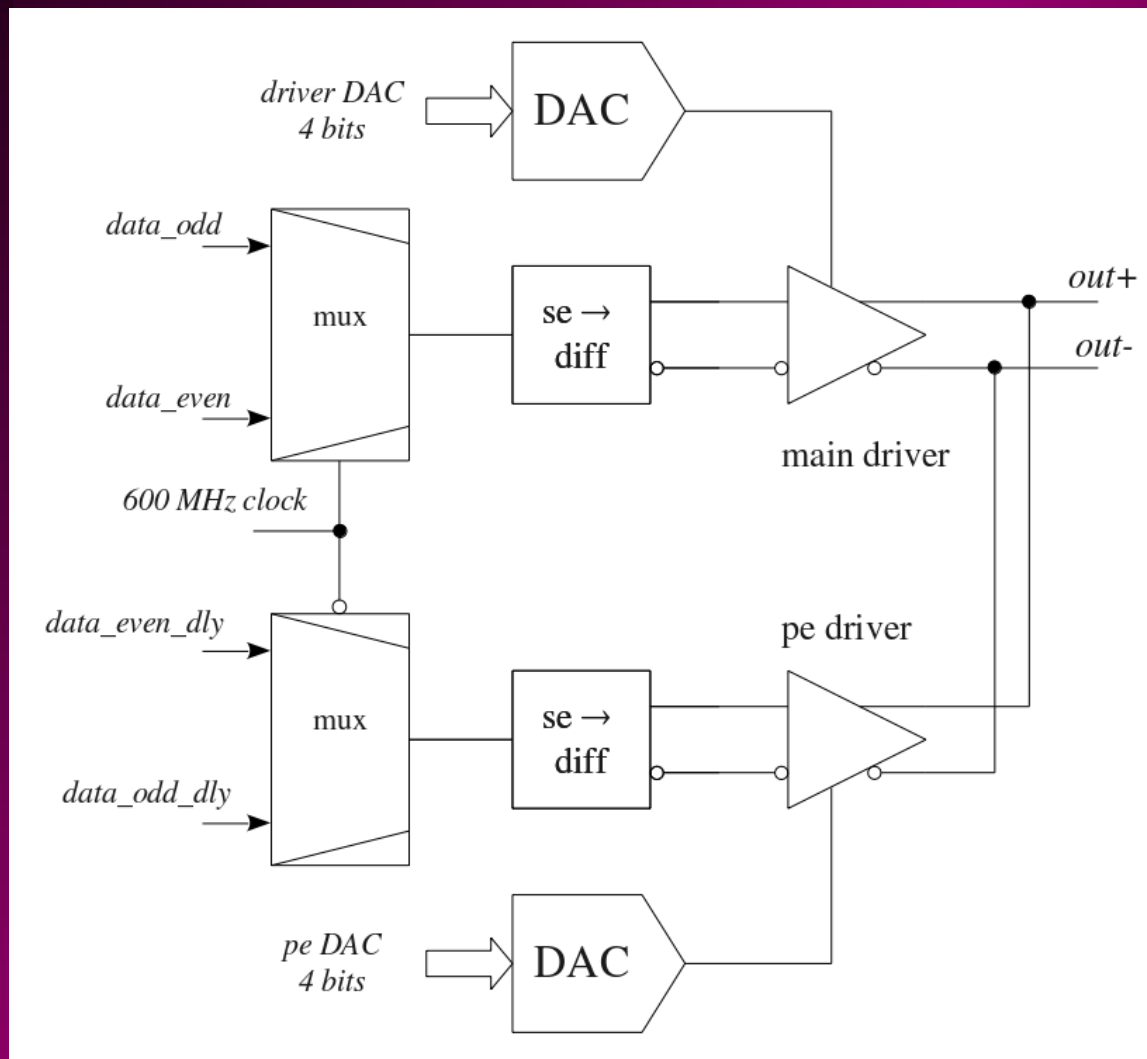
- * Double Data Rate
- * TMR-based SEU protection
- * Programmable phase control synchronization
- * Power : 22.56 mW @1.2V



Driver scheme



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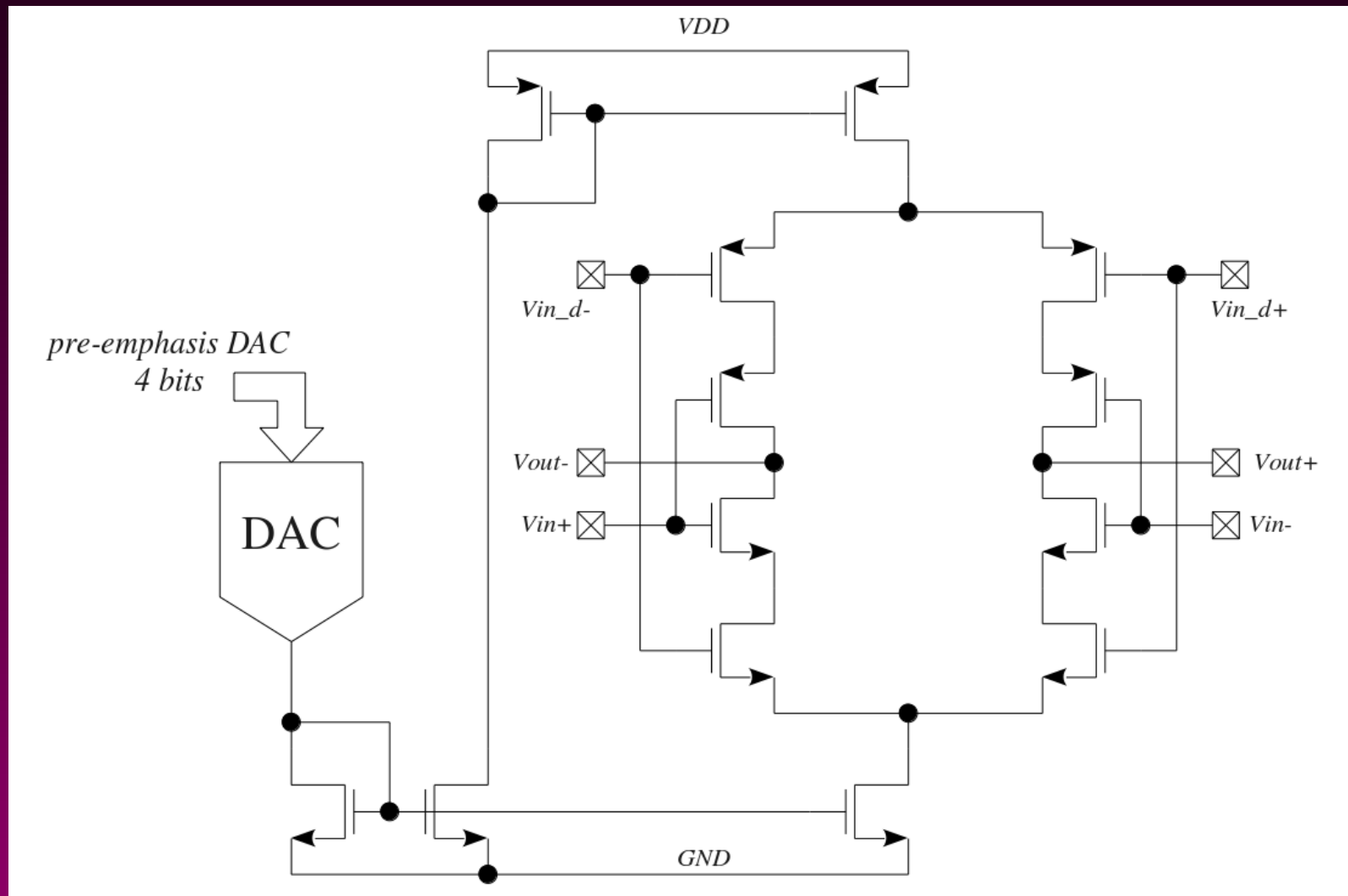
- * Pseudo-LVDS driver
- * CM voltage 900 mV
- * Output current : 0÷5 mA in 312 μ A steps (4 bits)
- * Pre-emphasis current : 0÷2.5 mA in 156 μ A steps (4 bits)
- * Pre-emphasis time width : $\frac{1}{2}$ clock cycle
- * Power : 17.06 mW @1.2V (*at half driving and pe current settings*)



Pre-emphasis driver schematic



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PLL v1 test summary - 1



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- * Input frequency : 40 MHz
- * Input frequency range : 30 MHz -50 MHz
- * Main output frequency : 600 MHz ($f_{IN} \times 15$)
- * Secondary output frequency : 200 MHz ($f_{IN} \times 5$)

	<i>Mean</i>	σ
<i>clock period</i>	<i>1.667 ns</i>	<i>6.8642 ps</i>
<i>clock frequency</i>	<i>600.01 MHz</i>	<i>2.4708 MHz</i>
<i>duty cycle</i>	<i>50.79%</i>	<i>0.0896 %</i>

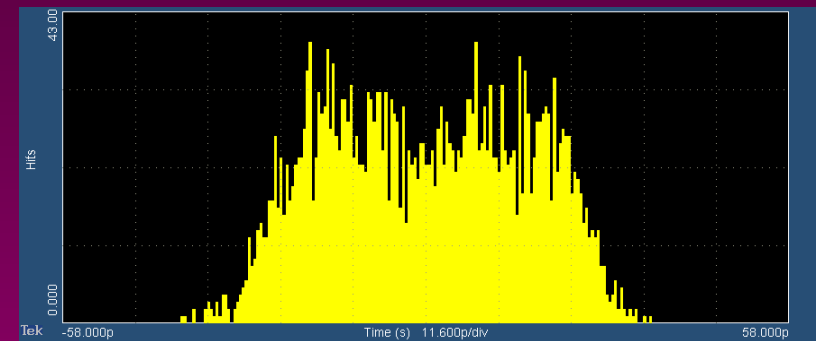
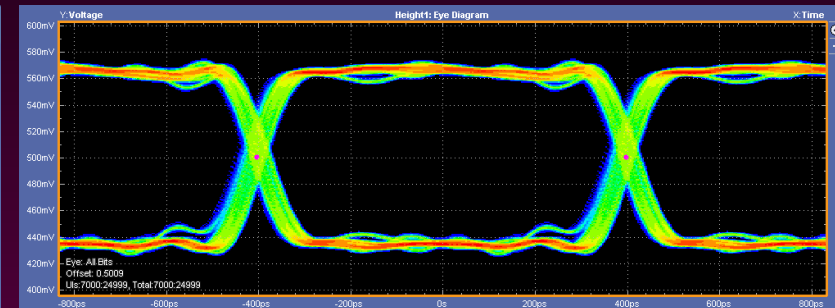
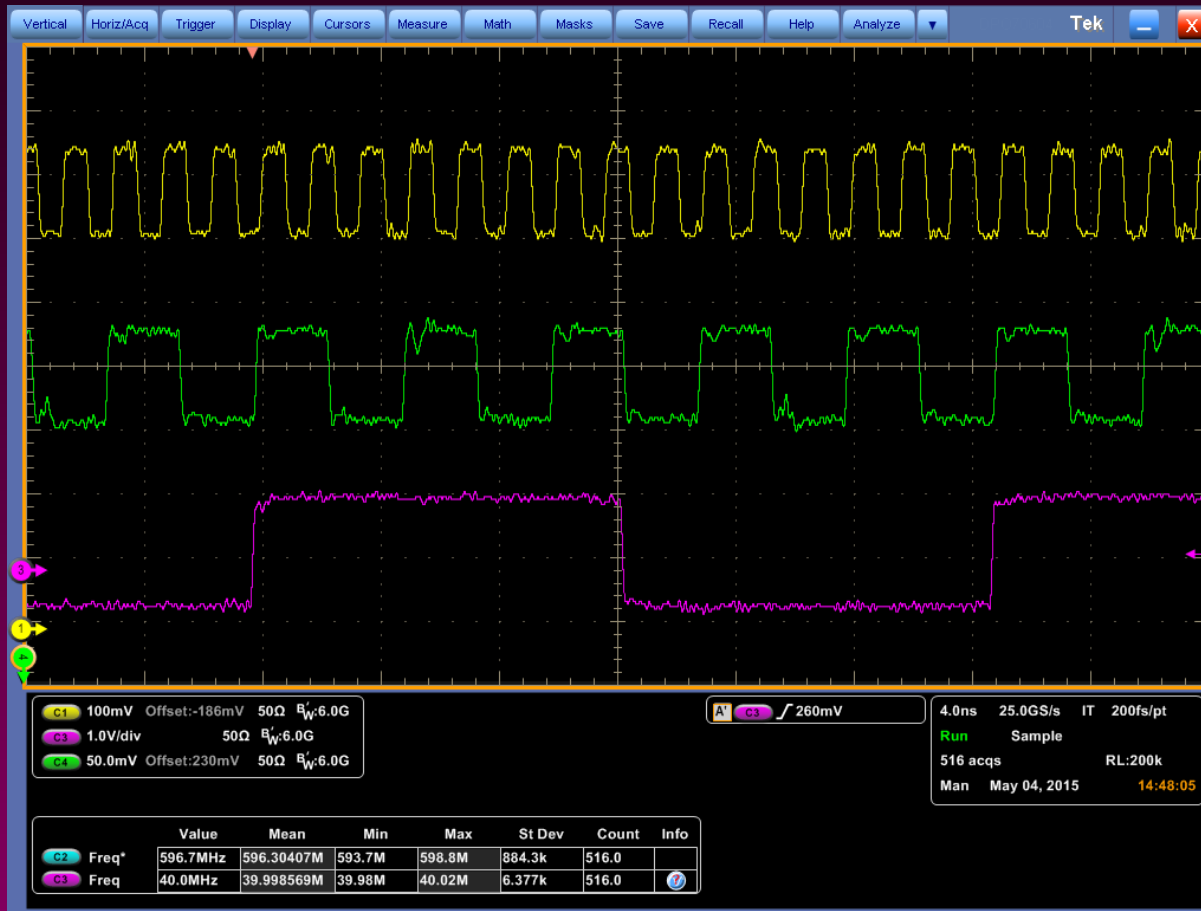
<i>Random jitter</i>	<i>4.736 ps (r.m.s.)</i>
<i>Periodic jitter</i>	<i>46.342 ps (pk-pk)</i>



PLL v1 test summary - 2



Sezione di Torino

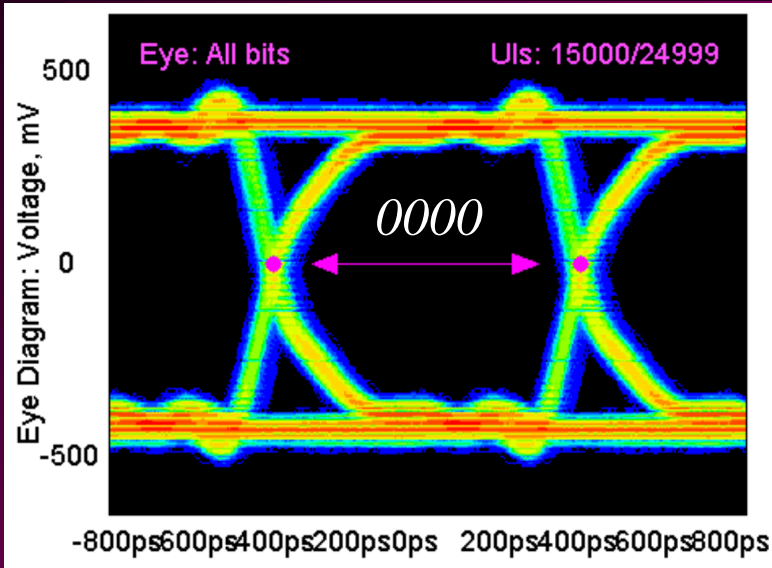




DTU test chip Electrical tests - 1



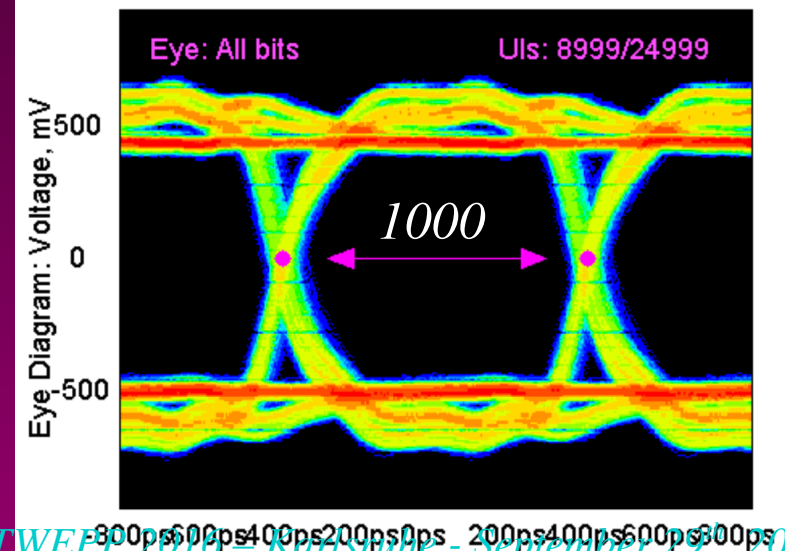
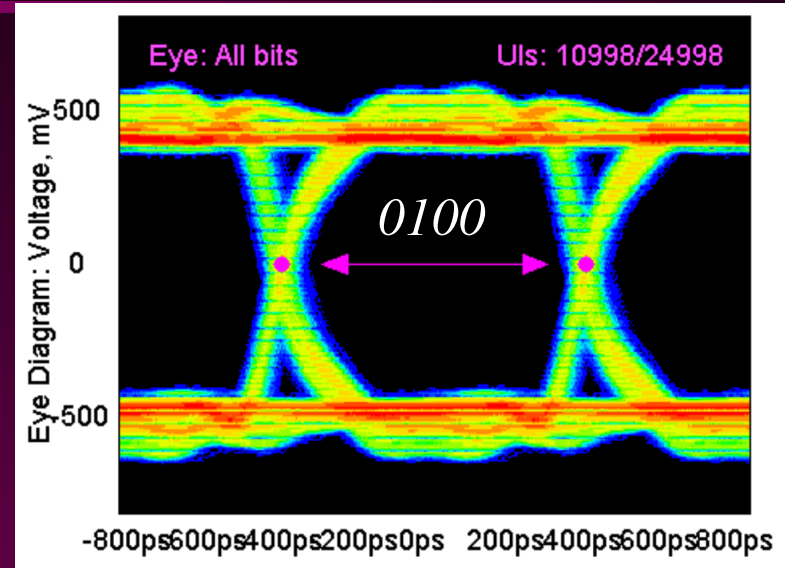
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Drv DAC : 1000

Rate : 1.25 Gb/s

BER : 10^{-12}



	<i>PE 0000</i>	<i>PE 0100</i>	<i>PE 1000</i>
<i>Eye width</i>	<i>0.822 UI</i>	<i>0.826 UI</i>	<i>0.835 UI</i>
<i>Eye opening</i>	<i>0.738 UI</i>	<i>0.742 UI</i>	<i>0.716 UI</i>
<i>R_j</i>	<i>11.4 ps</i>	<i>10.9 ps</i>	<i>12.0 ps</i>
<i>D_j</i>	<i>48.8 ps</i>	<i>52.8 ps</i>	<i>57.4 ps</i>

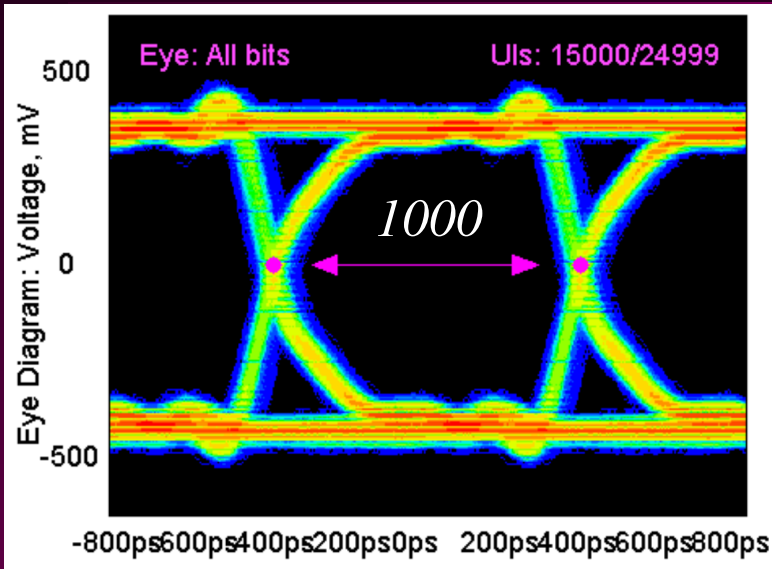


DTU test chip

Electrical tests - 2



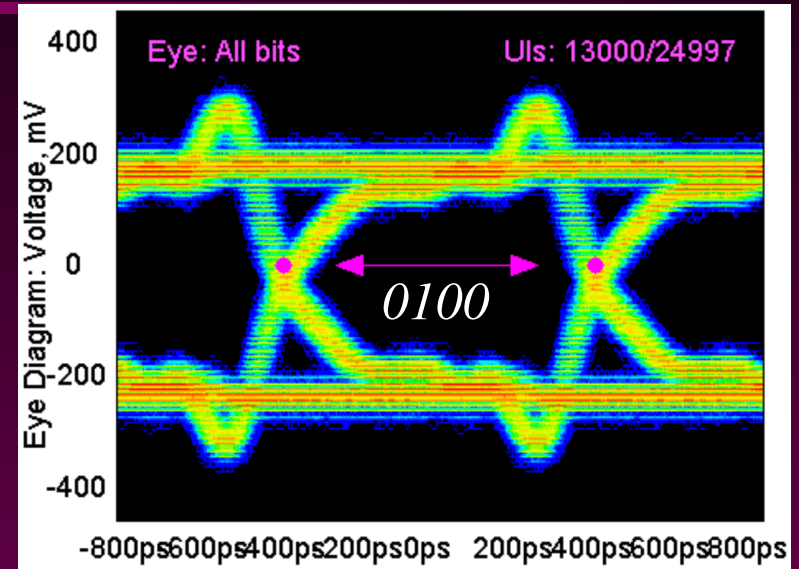
Sezione di Torino



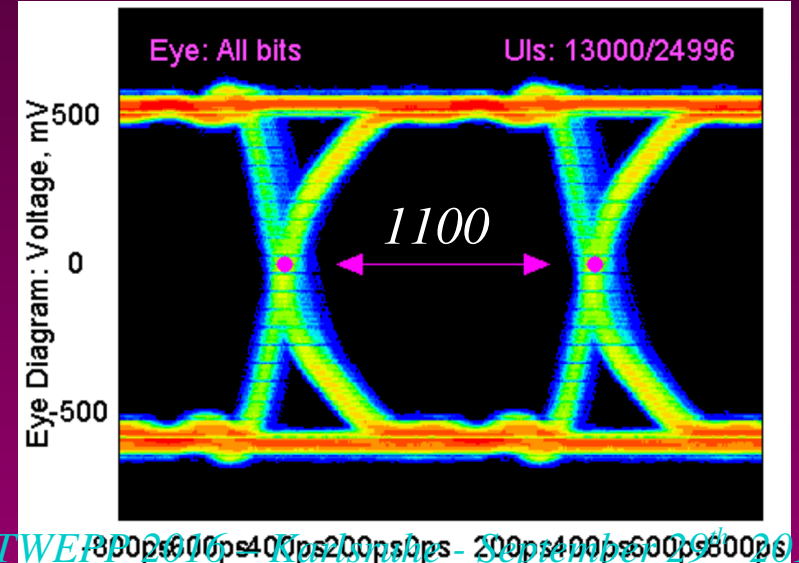
PE DAC : 0000

Rate : 1.25 Gb/s

BER : 10^{-12}



	<i>DRV 1000</i>	<i>DRV 0100</i>	<i>DRV 1100</i>
<i>Eye width</i>	<i>0.822 UI</i>	<i>0.759 UI</i>	<i>0.819 UI</i>
<i>Eye opening</i>	<i>0.738 UI</i>	<i>0.645 UI</i>	<i>0.688 UI</i>
<i>R_j</i>	<i>11.4 ps</i>	<i>12.8 ps</i>	<i>11.4 ps</i>
<i>D_j</i>	<i>48.8 ps</i>	<i>102.7 ps</i>	<i>88.7 ps</i>

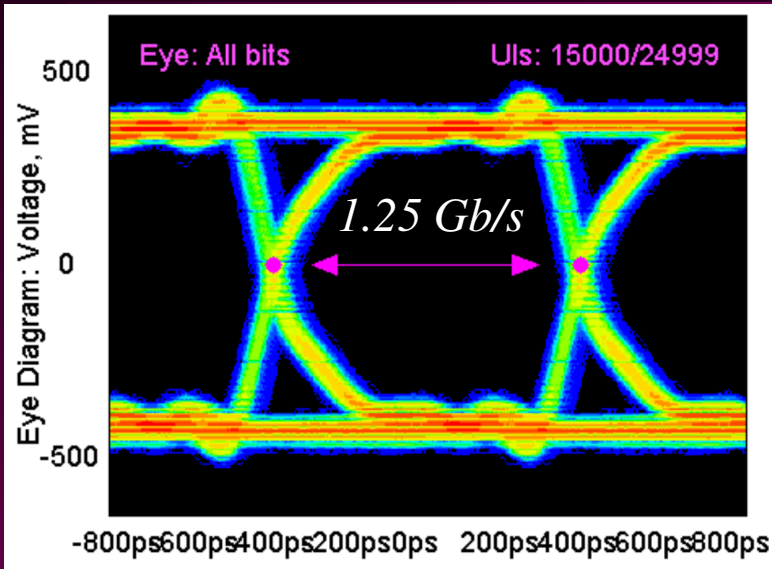




DTU test chip Electrical tests - 3



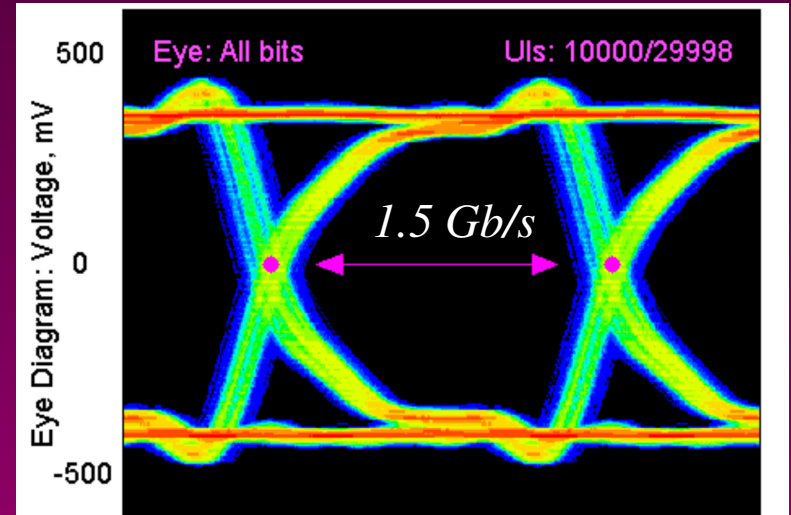
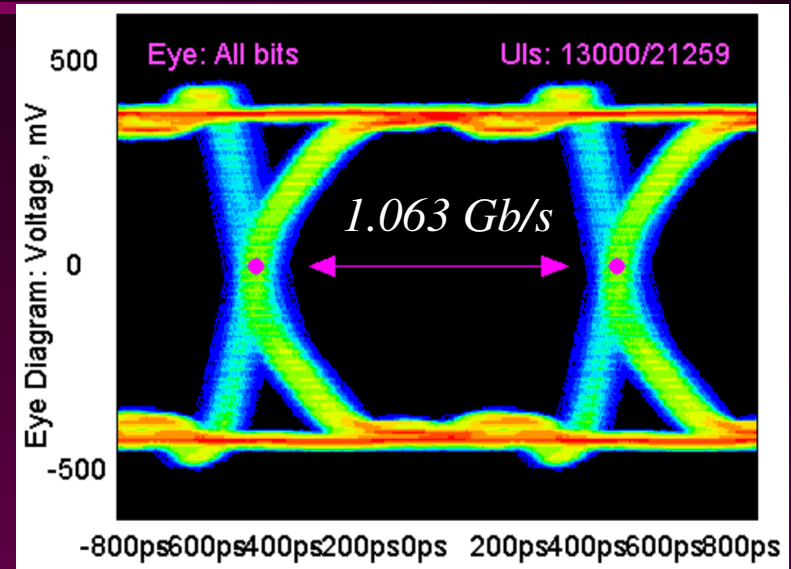
Sezione di Torino



DRV DAC : 1000

PE DAC : 0000

BER : 10^{-12}



	1.25 Gb/s	1.063 Gb/s	1.5 Gb/s
Eye width	0.822 UI	0.814 UI	0.789 UI
Eye opening	0.738 UI	0.713 UI	0.708 UI
R_j	11.4 ps	14.2 ps	8.8 ps
D_j	48.8 ps	69.6 ps	71.5 ps



Irradiation tests



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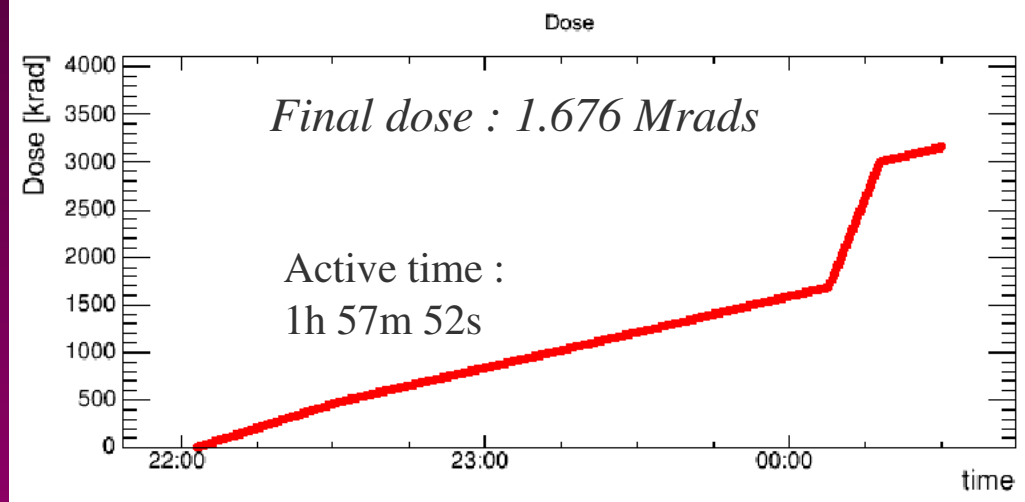
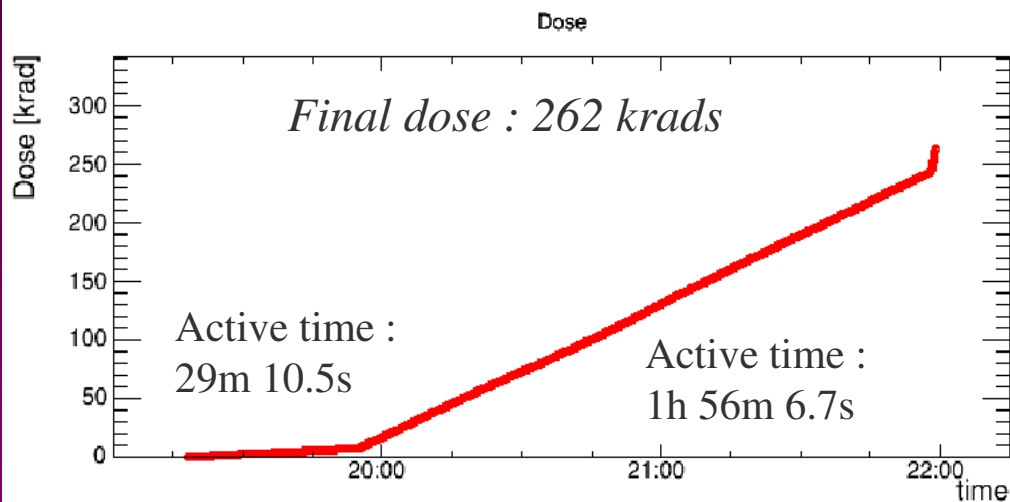
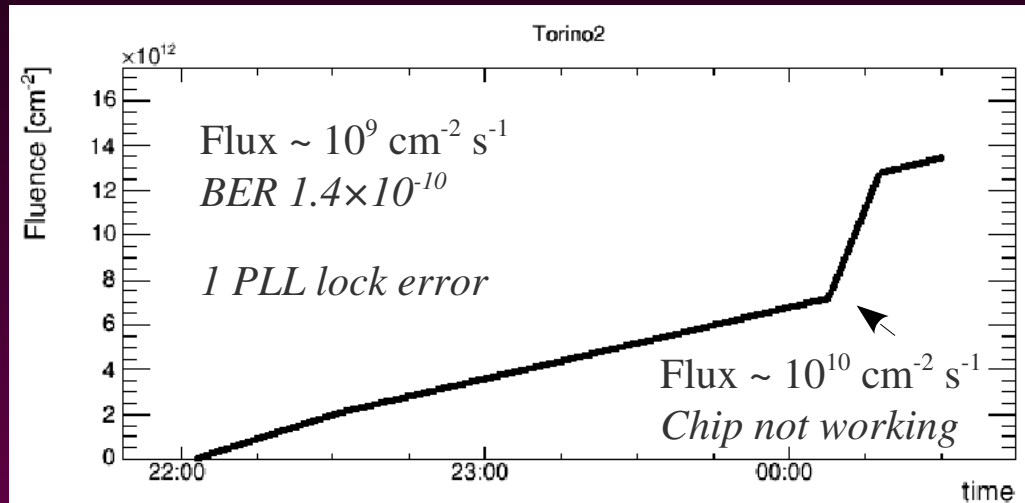
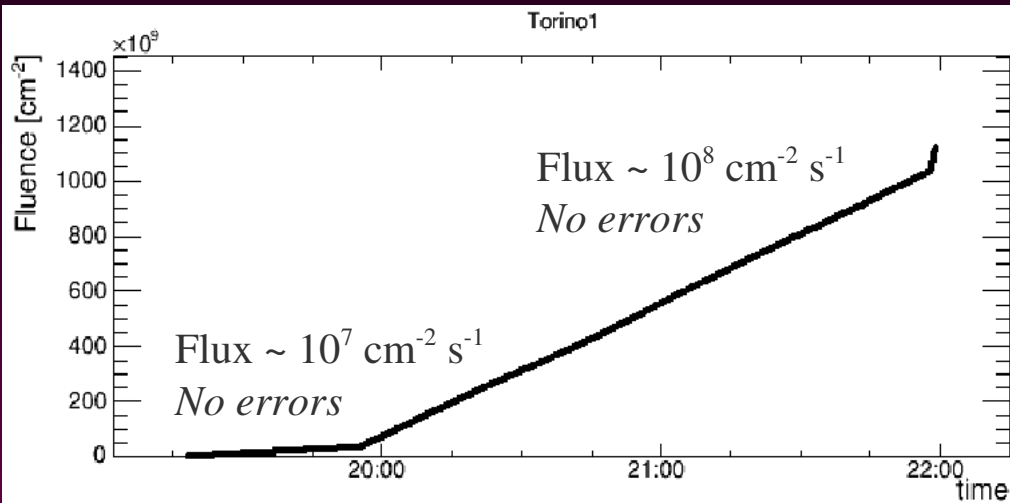
- * November 2015 : SEU test @ LNL Legnaro with ions
 - *chip partially damaged + set-up problems → results discarded*
- * February 2016 : TID and SEU tests @ NPI Prague with 30 MeV protons
- * July 2016 : SEU test @ LNL with ions



Test with 30 MeV protons



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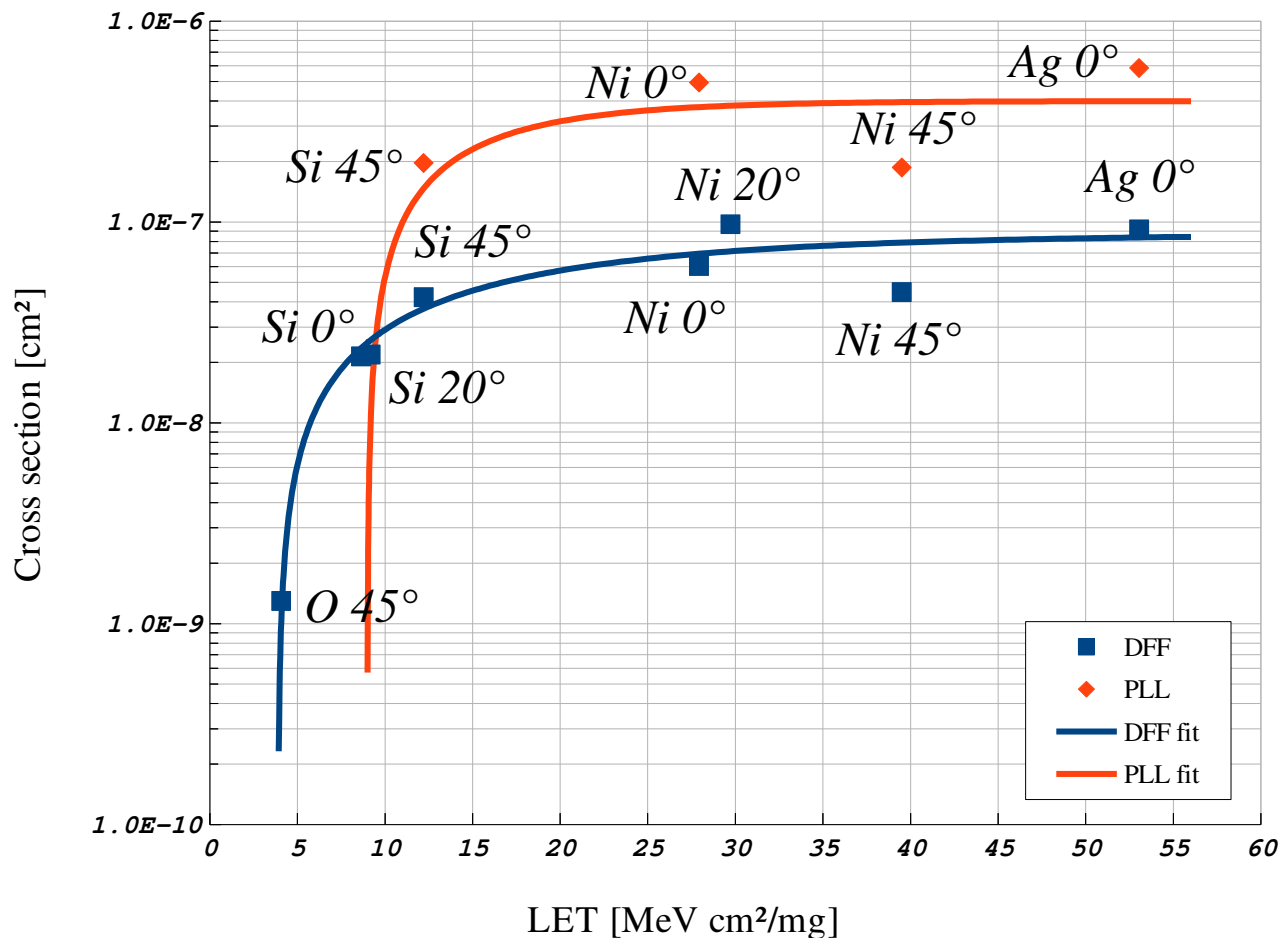




PLL & DFF cross section



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$LET_{TH} \approx 3.9 \text{ MeV cm}^2/\text{mg}$
for the DFF

Note : DFF cross section is per bit

$LET_{TH} \approx 9 \text{ MeV cm}^2/\text{mg}$
for the PLL lock

*Estimated PLL loss of lock
MTBF in layer 0 (108
DTUs) : 149h 33m*

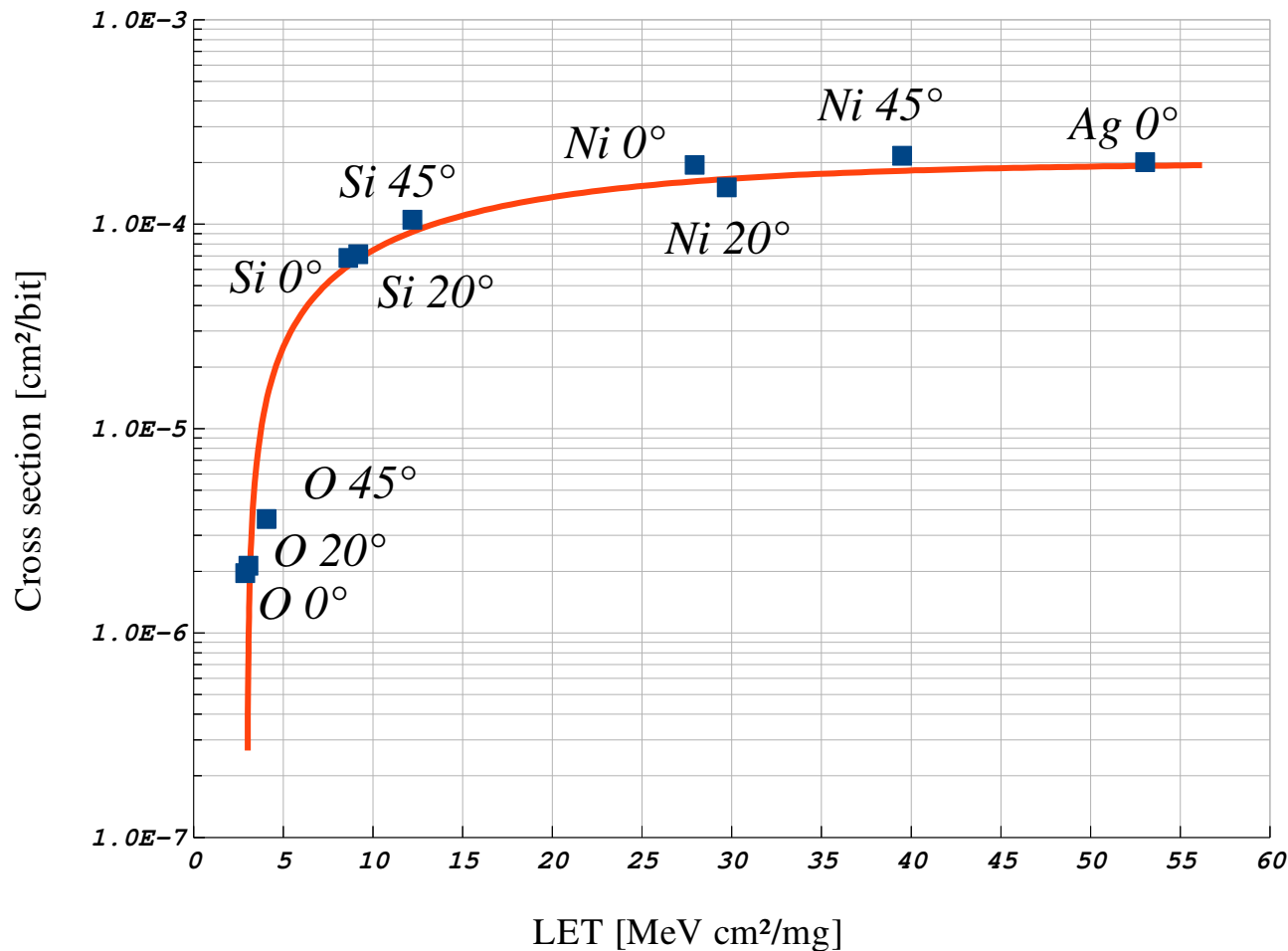
Only 1 (out of 37) GTX
loss of lock



BER cross section (preliminary)



Sezione di Torino



$LET_{TH} \approx 3 \text{ MeV cm}^2/\text{mg}$
for the serial data

Note : cross section is per bit

*Estimated transmission
MTBF in layer 0 (108
DTUs) : 42.8 s*

*Estimated BER per link :
 3.53×10^{-14}*

Receiver not optimized

*Still to be fully understood
(flux dependency ?)*



Conclusions



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- * A 1.2 Gb/s Data Transmission Unit (DTU) for the upgrade of the ALICE Inner Tracking System has been designed in 0.18 μm technology and tested
- * The DTU consists of a PLL for clock multiplication, a DDR serializer and a pseudo-LVDS driver with pre-emphasis
- * Electrical tests show that the DTU fullfills the specifications
- * TID tests shows a radiation tolerance up to ~ 1 Mrad
- * SEU tests shows a good behaviour in the expected ALICE environment. *Still something to be understood on BER aspect.*
- * New DTU version (with supply better noise insulation) submitted in the Alpide chip. Test ongoing.



Spare slides



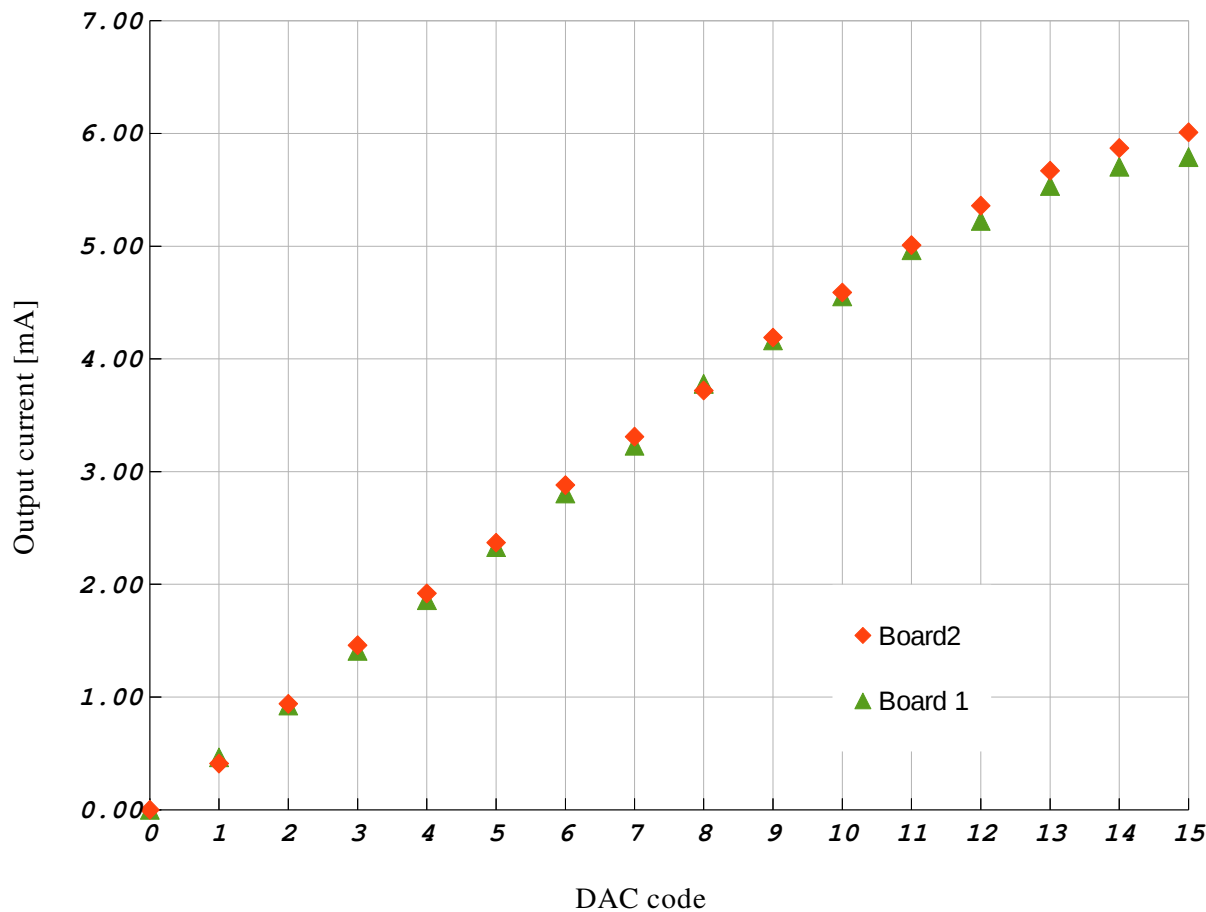
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Output amplitude



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Output current vs DAC code

Slope : 0.39 mA/DAC code

0.40 mA/DAC code

Intercept : 0.37 mA

0.39 mA

Note : current measurement absolute value not fully accurate (*too fast to have full voltage setting*)



SEU test in Legnaro ion list



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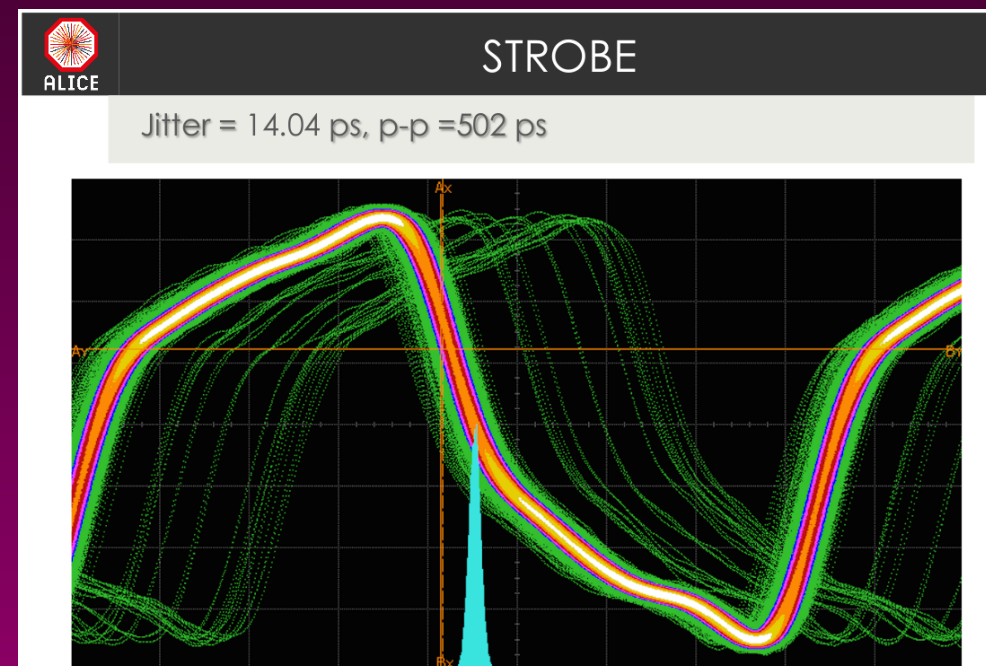
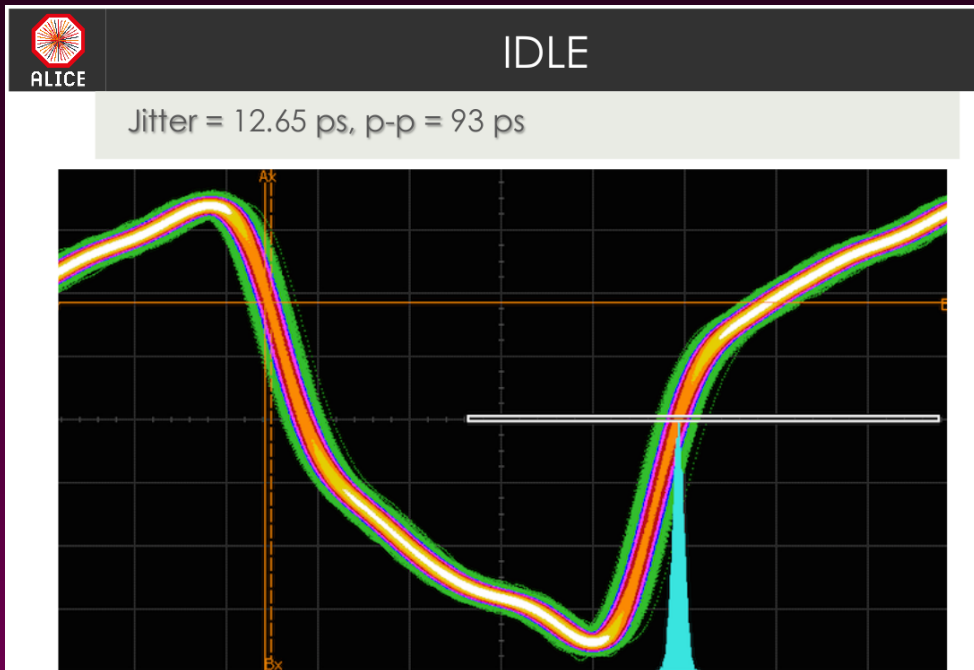
Ion	Angle	Energy [MeV]	LET [MeV cm ² /mg]
Ag	0°	266	53.04
Ni	45°	220	39.50
Ni	20°	220	29.72
Ni	0°	220	27.93
Si	45°	157	12.20
Si	20°	157	9.18
Si	0°	157	8.63
O	45°	108	4.07
O	20°	108	3.06
O	0°	108	2.88



Test results on Alpide



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Workarounds



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- * The degradation is a function of the chip activity.
- * Simulations show that the most critical component in terms of PSRR is the control line of the VCO
- * Actions :
 - Filter on the VCO_ctrl line (*limited by stability issues*)
 - try to reduce the noise coupling of the VCO_ctrl line
 - improve decap cells distribution on the digital part
 - separate supply for the PLL at the chip level



Bit error table for protons



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<i>Bit</i>	<i># Errors</i>	<i>Bit</i>	<i># Errors</i>	<i>Bit</i>	<i># Errors</i>
0	0	10	23	20	7.03×10^7
1	16	11	35	21	3.04×10^9
2	3.04×10^9	12	7.03×10^7	22	2.97×10^9
3	7.03×10^7	13	0	23	2.97×10^9
4	0	14	35	24	7.03×10^7
5	0	15	3.04×10^9	25	3.04×10^9
6	29	16	7.03×10^7	26	2.97×10^9
7	3.04×10^9	17	3.04×10^9	27	2.97×10^9
8	7.03×10^7	18	2.97×10^9	28	2.97×10^9
9	0	19	2.97×10^9	29	7.03×10^7